

<b>Notice of References Cited</b>	Application/Control No. 10/616,492	Applicant(s)/Patent Under Reexamination LEE, YAO-SHENG	
	Examiner Binh X. Tran	Art Unit 1765	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0094690	07-2002	Athavale et al.	438/710
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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